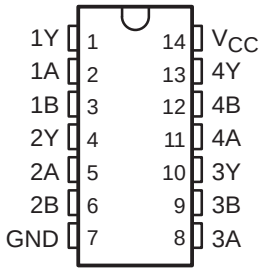
CD54ACT02, CD74ACT02
QUADRUPLE 2-INPUT POSITIVE-NOR GATES

SCHS309 – JANUARY 2001

- **Inputs Are TTL-Voltage Compatible**
- **Speed of Bipolar FCT, AS, and S, With Significantly Reduced Power Consumption**
- **Balanced Propagation Delays**
- **±24-mA Output Drive Current**
  - **Fanout to 15 FCT Devices**
  - **Drives 50-Ω Transmission Lines**
- **SCR-Latchup-Resistant CMOS Process and Circuit Design**
- **Exceeds 2-kV ESD Protection Per MIL-STD-883, Method 3015**

CD54ACT02 . . . F PACKAGE
CD74ACT02 . . . E OR M PACKAGE
(TOP VIEW)



description

The ’ACT02 devices contain four independent 2-input NOR gates that perform the Boolean function $Y = \overline{A} \bullet \overline{B}$ or $Y = \overline{A + B}$ in positive logic.

ORDERING INFORMATION

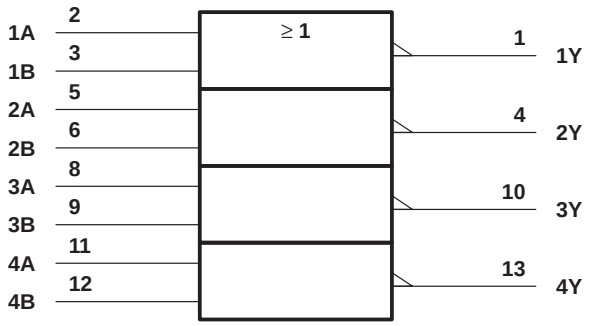
T_A	PACKAGE†		ORDERABLE PART NUMBER	TOP-SIDE MARKING
–40°C to 85°C	PDIP – E	Tube	CD74ACT02E	CD74ACT02E
	SOIC – M	Tube	CD74ACT02M	ACT02M
		Tape and reel	CD74ACT02M96	
–55°C to 125°C	CDIP – F	Tube	CD54ACT02F3A	CD54ACT02F3A

† Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/sc/package.

FUNCTION TABLE
(each gate)

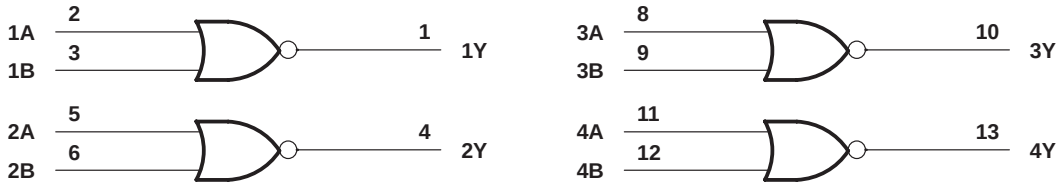
INPUTS		OUTPUT
A	B	Y
H	X	L
X	H	L
L	L	H

logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage range, V_{CC} . . . . . –0.5 V to 6 V
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$) (see Note 1) . . . . . ±20 mA
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$) (see Note 1) . . . . . ±50 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC}) . . . . . ±50 mA
Continuous current through V_{CC} or GND . . . . . ±100 mA
Package thermal impedance, θ_{JA} (see Note 2): E package . . . . . 80°C/W
M package . . . . . 86°C/W
Storage temperature range, T_{stg} . . . . . –65°C to 150°C

‡ Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. The package thermal impedance is calculated in accordance with JESD 51-7.

recommended operating conditions (see Note 3)

		T_A = 25°C		CD54ACT02		CD74ACT02		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	
V_{CC}	Supply voltage	4.5	5.5	4.5	5.5	4.5	5.5	V
V_{IH}	High-level input voltage	2		2		2		V
V_{IL}	Low-level input voltage		0.8		0.8		0.8	V
V_I	Input voltage	0	V_{CC}	0	V_{CC}	0	V_{CC}	V
V_O	Output voltage	0	V_{CC}	0	V_{CC}	0	V_{CC}	V
I_{OH}	High-level output current		–24		–24		–24	mA
I_{OL}	Low-level output current		24		24		24	mA
$\Delta t/\Delta v$	Input transition rise or fall rate	0	10	0	10	0	10	ns/V
T_A	Operating free-air temperature			–55	125	–40	85	°C

NOTE 3: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		V_{CC}	T_A = 25°C		CD54ACT02		CD74ACT02		UNIT
				MIN	MAX	MIN	MAX	MIN	MAX	
V_{OH}	$V_I = V_{IH}$ or V_{IL}	I_{OH} = –50 μA	4.5 V	4.4		4.4		4.4		V
		I_{OH} = –24 mA	4.5 V	3.94		3.7		3.8		
		I_{OH} = –50 mA†	5.5 V			3.85				
		I_{OH} = –75 mA†	5.5 V					3.85		
V_{OL}	$V_I = V_{IH}$ or V_{IL}	I_{OL} = 50 μA	4.5 V		0.1		0.1		0.1	V
		I_{OL} = 24 mA	4.5 V		0.36		0.5		0.44	
		I_{OL} = 50 mA†	5.5 V				1.65			
		I_{OL} = 75 mA†	5.5 V						1.65	
I_I	$V_I = V_{CC}$ or GND		5.5 V		±0.1		±1		±1	μA
I_{CC}	$V_I = V_{CC}$ or GND,	I_O = 0	5.5 V		4		80		40	μA
ΔI_{CC}	$V_I = V_{CC}$ – 2.1 V		4.5 V to 5.5 V		2.4		3		2.8	mA
C_i					10		10		10	pF

† Test one output at a time, not exceeding 1-second duration. Measurement is made by forcing indicated current and measuring voltage to minimize power dissipation. Test verifies a minimum 50-Ω transmission-line drive capability at 85°C and 75-Ω transmission-line drive capability at 125°C.

ACT INPUT LOAD TABLE

INPUT	UNIT LOAD
A or B	0.32

Unit load is ΔI_{CC} limit specified in electrical characteristics table (e.g., 2.4 mA at 25°C).

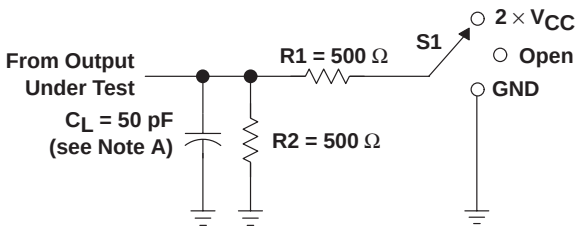
switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V ± 0.5 V, C_L = 50 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	CD54ACT02		CD74ACT02		UNIT
			MIN	MAX	MIN	MAX	
t_{PLH}	A or B	Y	3.1	12.2	3.1	11.1	ns
t_{PHL}			3.1	12.2	3.1	11.1	

operating characteristics, V_{CC} = 5 V, T_A = 25°C

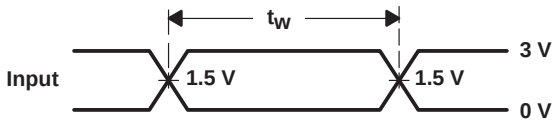
PARAMETER		TYP	UNIT
C_{pd}	Power dissipation capacitance	55	pF

PARAMETER MEASUREMENT INFORMATION

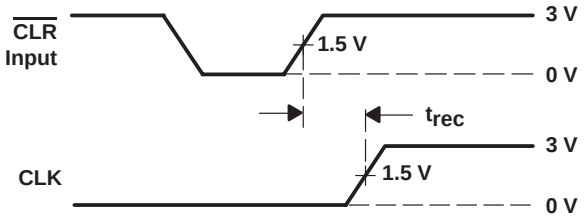


LOAD CIRCUIT

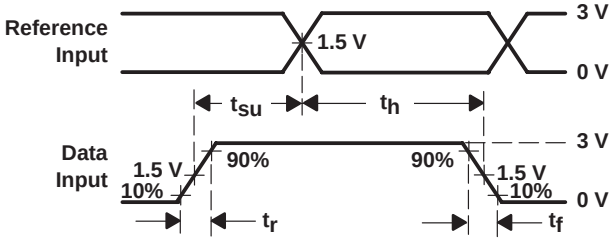
TEST	S1
t_{PLH}/t_{PHL}	Open
t_{PLZ}/t_{PZL}	2 × V_{CC}
t_{PHZ}/t_{PZH}	GND



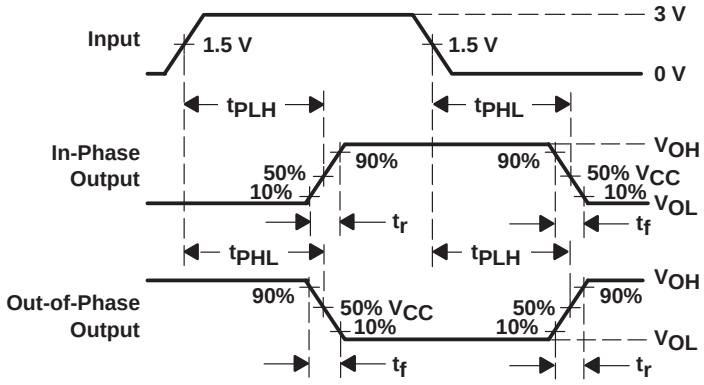
VOLTAGE WAVEFORMS
PULSE DURATION



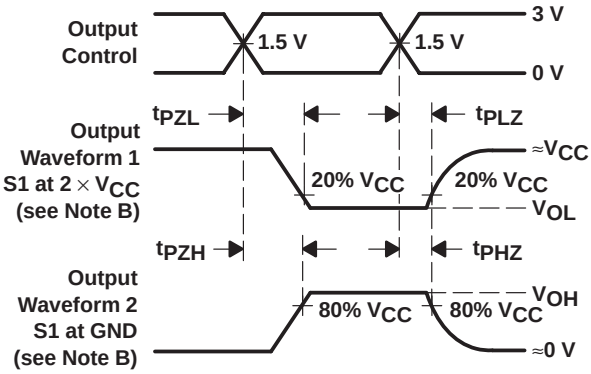
VOLTAGE WAVEFORMS
RECOVERY TIME



VOLTAGE WAVEFORMS
SETUP AND HOLD AND INPUT RISE AND FALL TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY AND OUTPUT TRANSITION TIMES



VOLTAGE WAVEFORMS
OUTPUT ENABLE AND DISABLE TIMES

NOTES: A. C_L includes probe and test-fixture capacitance.
B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
C. All input pulses are supplied by generators having the following characteristics: PRR ≤ 1 MHz, Z_O = 50 Ω, t_r = 3 ns, t_f = 3 ns. Phase relationships between waveforms are arbitrary.
D. For clock inputs, f_{max} is measured with the input duty cycle at 50%.
E. The outputs are measured one at a time with one input transition per measurement.
F. t_{PLH} and t_{PHL} are the same as t_{pd}.
G. t_{PZL} and t_{PZH} are the same as t_{en}.
H. t_{PLZ} and t_{PHZ} are the same as t_{dis}.

Figure 1. Load Circuit and Voltage Waveforms

IMPORTANT NOTICE

Texas Instruments and its subsidiaries (TI) reserve the right to make changes to their products or to discontinue any product or service without notice, and advise customers to obtain the latest version of relevant information to verify, before placing orders, that information being relied on is current and complete. All products are sold subject to the terms and conditions of sale supplied at the time of order acknowledgment, including those pertaining to warranty, patent infringement, and limitation of liability.

TI warrants performance of its products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

Customers are responsible for their applications using TI components.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards must be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance or customer product design. TI does not warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such products or services might be or are used. TI's publication of information regarding any third party's products or services does not constitute TI's approval, license, warranty or endorsement thereof.

Reproduction of information in TI data books or data sheets is permissible only if reproduction is without alteration and is accompanied by all associated warranties, conditions, limitations and notices. Representation or reproduction of this information with alteration voids all warranties provided for an associated TI product or service, is an unfair and deceptive business practice, and TI is not responsible nor liable for any such use.

Resale of TI's products or services with *statements different from or beyond the parameters* stated by TI for that product or service voids all express and any implied warranties for the associated TI product or service, is an unfair and deceptive business practice, and TI is not responsible nor liable for any such use.

Also see: Standard Terms and Conditions of Sale for Semiconductor Products. www.ti.com/sc/docs/stdterms.htm

Mailing Address:

Texas Instruments
Post Office Box 655303
Dallas, Texas 75265